

## Qualification Results Summary for ADuM5230 Die Revision and Data Sheet Change

QUALIFICATION RESULTS			
TEST	CONDITIONS	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	8 x 77 1x45	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	9x77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	9x77	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	9x77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	2x77 6x45	Pass
SHR (Solder Heat Resistance)*	JEDEC/IPC <i>J-STD-020</i>	1x30	Pass
Latch up	JEDEC Standard 78	1x12	Pass +/- 100mA @ +18V
Electrostatic Discharge <i>Human Body Model</i>	ESD Association <i>STM5.1-2007</i>	1x18	Pass ±2500V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	ESD Association <i>STM5.3.1-1999</i>	1x18	Pass ±1250V
Electrostatic Discharge Machine Model	JESD22-A115	1x18	Pass ±100V

\*Preconditioned per JEDEC/IPC J-STD-020